

AMENDMENT AND PRESENTATION OF CLAIMS

Please replace all prior claims in the present application with the following claims, in which no claims are canceled or withdrawn from consideration, claims 1 and 2 are currently amended, and claims 11-20 are newly presented.

1. (Currently Amended) A high-frequency measuring system for measuring a device under test, comprising:

a measuring-device unit; and

at least one high-frequency module, wherein each high-frequency module is placed spatially separated from the measuring-device unit and each high-frequency module is connected to the measuring-device unit via a digital interface for transmitting data to the at least one high-frequency module, wherein

~~processing of input data originating from manually input into~~ the measuring-device unit ~~is processed in the measuring-unit device~~ to form a bitstream for transmission via the digital interface ~~to the at least one high-frequency module for subsequent forwarding to the device under test, the processing of the input data includes including~~ assigning symbols to states in a state diagram of an I-Q (in phase – quadrature phase) level in the measuring-device unit~~[[,]] or a digitized intermediate-frequency signal is transmitted via the digital interface.~~

2. (Currently Amended) A high-frequency measuring system according to claim 1, wherein the at least one high-frequency module comprises a transmitter device ~~or a receiver device~~ for communication with the device under test.

3. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the digital interface is a serial interface.

4. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the digital interface is a parallel interface.

5. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the digital interface is an optical interface.

6. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the digital interface is an electrical interface.

7. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the at least one high-frequency module is supplied with electrical energy via a power-supply unit independent from the measuring-device unit.

8. (Previously Presented) A high-frequency measuring system according to claim 1, wherein a plurality of identical ports are provided on the measuring-device unit for the digital interface.

9. (Previously Presented) A high-frequency measuring system according to claim 1, wherein a plurality of different ports are provided on the measuring-device unit for the digital interface.

10. (Previously Presented) A high-frequency measuring system according to claim 1, wherein control data or user data is transmitted in a standardized form via the digital interface,

and wherein the at least one high-frequency module comprises means for processing a high-frequency signal with regard to the transmission of data in standardized form via the digital interface or for processing the data transmitted in standardized form with regard to at least one predetermined transmission standard for the high-frequency signal.

11. (New) A high-frequency measuring system according to claim 1, wherein the input data is manually input by any one of operating keys, a rotary knob, or arrow keys.

12. (New) A high-frequency measuring system for measuring a device under test, comprising:

a measuring-device unit for receiving input data from a user; and

at least one high-frequency module, wherein each high-frequency module is placed spatially separated from the measuring-device unit and each high-frequency module is connected to the measuring-device unit via a digital interface,

wherein a message comprising a high-frequency signal originating from the device under test is transmitted to the at least one high-frequency module, the high-frequency signal being processed by the at least one high-frequency module to form a first bitstream for transmission via the digital interface to the measuring-device unit, the processing, by the at least one high-frequency module, including converting the high-frequency signal to an intermediate-frequency signal and digitizing the intermediate-frequency signal for transmission via the digital interface to the measuring-device unit for evaluation of the message, and

wherein the input data is processed in the measuring-unit device to form a second bitstream for transmission via the digital interface to the at least one high-frequency module for subsequent forwarding to the device under test.

13. (New) A high-frequency measuring system according to claim 12, wherein the at least one high-frequency module comprises a transmitter device or a receiver device for communication with the device under test.

14. (New) A high-frequency measuring system according to claim 13, wherein the conversion of the high-frequency signal to an intermediate-frequency signal includes receiving the high-frequency signal at the receiver device and subsequently mixing the high-frequency signal with a signal generated by a first local oscillator.

15. (New) A high-frequency measuring system according to claim 14, wherein the intermediate-frequency signal is subdivided into an in-phase branch and a quadrature-phase branch and mixed in the in-phase branch with a signal generated by a second local oscillator.

16. (New) A method for testing a device, comprising:

receiving input data from a user;

forming, based on the input data, a first bitstream for transmission via a digital interface to at least one high-frequency module for subsequent forwarding to the device; wherein the first bitstream forming includes assigning symbols to states relating to an I-Q (in phase – quadrature phase) level; and

receiving a second bitstream representative of high-frequency signal messages originating from the device via the at least one high-frequency module, the at least one high-frequency module processing the high-frequency signal messages to form the second bitstream, the processing, by the at least one high-frequency module, including converting the high-frequency

signal messages to intermediate-frequency signals and digitizing the intermediate-frequency signals.

17. (New) A method according to claim 16, further comprising:
determining a specific bit sequence to be transmitted to the device under test.
18. (New) A method according to claim 17, further comprising:
generating one or more control signals in the bit sequence to control the at least one high-frequency module.
19. (New) A method according to claim 16, wherein the input data is input by the user using any one of operating keys, a rotary knob, or arrow keys.
20. (New) A method according to claim 16, wherein the at least one high-frequency module comprises a transmitter device or a receiver device for communication with the device under test.